

240N12NS3-VB Datasheet N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{(BR)DSS} (V)	$r_{DS(on)}(\Omega)$	I _D (A)			
100	0.017 at V _{GS} = 10 V	30			

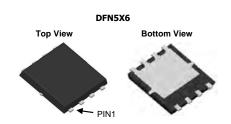
FEATURES

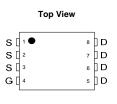
- Trench Power MOSFET
- 175 °C Junction Temperature
- Low Thermal Resistance Package
- 100 % R_g Tested

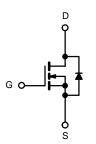


APPLICATIONS

• Isolated DC/DC Converters







N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	iS (T _A = 25 °C, u	nless other	wise noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V _{DS}	100	V	
Gate-source voltage		V_{GS}	± 20		
	T _C = 25 °C		30		
Continuous drain surrent (T. 150 °C)	T _C = 70 °C	Ι.	19		
Continuous drain current (T _J = 150 °C)	T _A = 25 °C	I _D	10 ^{b, c}		
	T _A = 70 °C		8.5 ^{b, c}		
Pulsed drain current (t = 100 μs)		I _{DM}	75	A	
Continuous source-drain diode current	T _C = 25 °C		56	1	
	T _A = 25 °C	l _S	4.5 b, c]	
Single pulse avalanche current L = 0.1 mH		I _{AS}	20		
Single pulse avalanche energy		E _{AS}	20	mJ	
Maximum power dissipation	T _C = 25 °C		60	W	
	T _C = 70 °C	Б	40		
	T _A = 25 °C	P _D	5 b, c		
	T _A = 70 °C	ĺ	3.2 b, c		
Operating junction and storage temperature range		T _J , T _{stg}	-55 to +150	°C	
Soldering recommendations (peak temperature) ^c			260		

THERMAL RESISTANCE RATINGS							
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT		
Maximum junction-to-ambient b	t ≤ 10 s	R_{thJA}	20	25	°C/W		
Maximum junction-to-case (drain)	Steady state	R _{thJC}	1.6	2	C/VV		

Notes

- a. Package limited
- b. Surface mounted on 1" x 1" FR4 board
- c. t = 10 s

服务热线:400-655-8788

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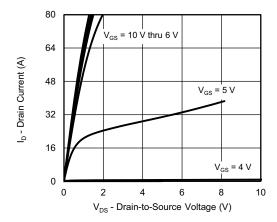
SPECIFICATIONS (T _J = 25 °C, PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static	STIVIBUL	TEST CONDITIONS	IVIIIN.	ITP.	IVIAA.	UNIT
Drain-source breakdown voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	100	_	_	V
V _{DS} temperature coefficient	ΔV _{DS} /T _J	I _D = 10 mA		81		-
V _{GS(th)} temperature coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-7.5	-	mV/°C
Gate-source threshold voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	3	-	5	V
Gate-source leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	100	nA
·	400	V _{DS} = 100 V, V _{GS} = 0 V	-	-	1	μΑ
Zero gate voltage drain current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 70 °C	-	-	15	
On-state drain current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	40	_	_	Α
		V _{GS} =10 V, I _D = 10 A	- 0.0170 -		-	
Drain-source on-state resistance ^a	R _{DS(on)}	$V_{GS} = 7.5 \text{ V}, I_D = 10 \text{ A}$	-	0.0200	-	Ω
Forward transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A	-	46	-	S
Dynamic ^b		-				II.
Input capacitance	C _{iss}		-	1470	-	
Output capacitance	C _{oss}	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz		132	-	pF
Reverse transfer capacitance	C _{rss}		-	11.2	-	† '
Total gate charge	0	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	20	-	
	Q_g		-	15	-	
Gate-source charge	Q _{gs}	V _{DS} = 50 V, V _{GS} = 7.5 V, I _D = 10 A		6.45	-	nC
Gate-drain charge	Q _{gd}			3.5	=.	
Output charge	Q _{oss}	V _{DS} = 50 V, V _{GS} = 0 V	-	22	-	
Gate resistance	Rg	f = 1 MHz	0.2	0.76	1.4	Ω
Turn-on delay time	t _{d(on)}		-	12	24	
Rise time	t _r	$V_{DD} = 50 \text{ V}, R_L = 5 \Omega, I_D \cong 10 \text{ A},$	-	5	10	
Turn-off delay time	t _{d(off)}	V_{GEN} = 10 V, R_g = 1 Ω	-	19	38	
Fall time	t _f		-	5	10	ns
Turn-on delay time	t _{d(on)}		-	15	30	115
Rise time	t _r	V_{DD} = 50 V, R_L = 5 Ω , I_D \cong 10 A,	-	6	12	
Turn-off delay time	t _{d(off)}	V_{GEN} = 7.5 V, R_g = 1 Ω	1	19	38	
Fall time	t _f		=	5	10	
Drain-Source Body Diode Characteris	tics					
Continuous source-drain diode current	Is	T _C = 25 °C	-	-	56.8	А
Pulse diode forward current	I _{SM}			-	80	^
Body diode voltage	V _{SD}	I _S = 5 A, V _{GS} = 0 V	-	0.78	1.1	V
Body diode reverse recovery time	t _{rr}		-	43	86	ns
Body diode reverse recovery charge	Q _{rr}	L = 10 A di/dt = 100 A/vo T = 25 °C	=	72	144	nC
Reverse recovery fall time	ta	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	=	33	=	ne
Reverse recovery rise time	t _b			10	-	ns

Notes

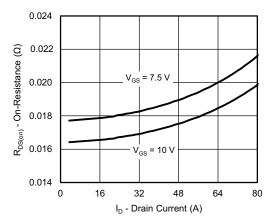
- a. Pulse test; pulse width $\leq 300~\mu s,\,duty~cycle \leq 2~\%$
- b. Guaranteed by design, not subject to production testing

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

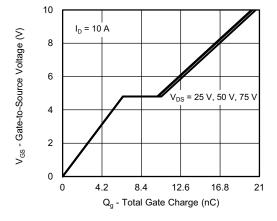




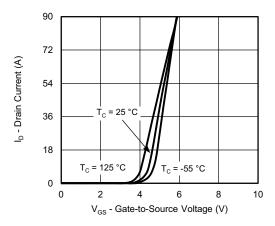
Output Characteristics



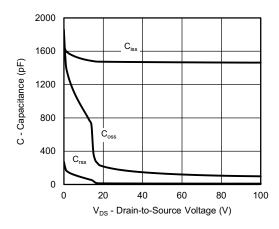
On-Resistance vs. Drain Current and Gate Volta ${\bf g}{\rm e}$



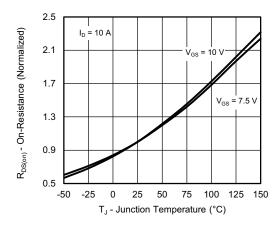
Gate Char**g**e



Transfer Characteristics

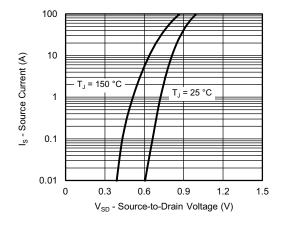


Capacitance

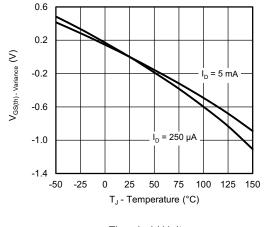


On-Resistance vs. Junction Temperature

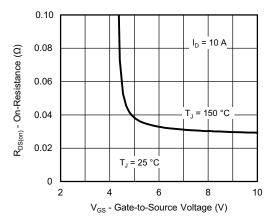




Source-Drain Diode Forward Voltage

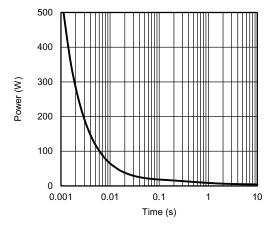


Threshold Voltage

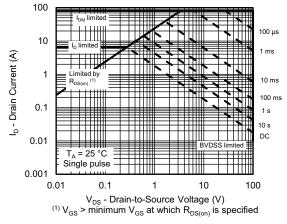


On-Resistance vs. Gate-to-Source Voltage

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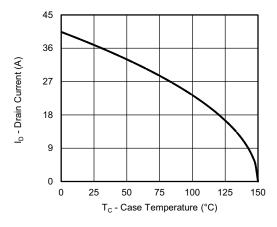


Single Pulse Power, Junction-to-Ambient

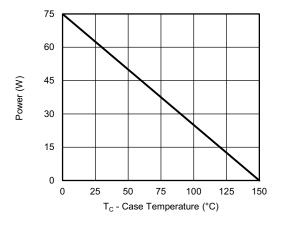


Safe Operating Area, Junction-to-Ambient

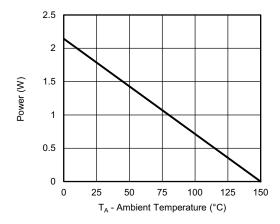




Current Derating ^a



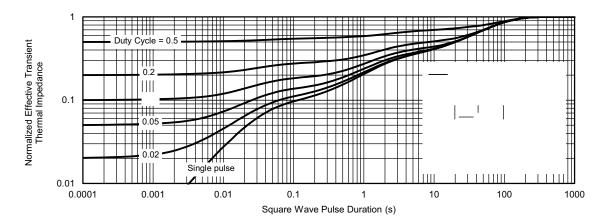
Power, Junction-to-Case



Power, Junction-to-Ambient

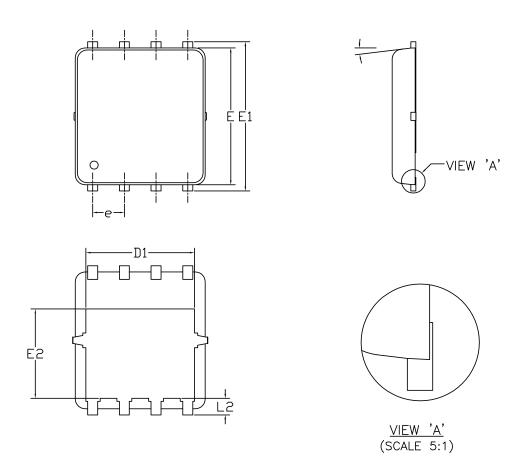
Note

a. The power dissipation P_D is based on T_J max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit

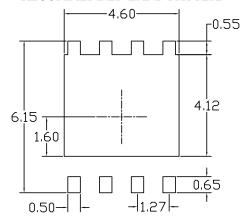


Normalized Thermal Transient Impedance, Junction-to-Ambient

Normalized Thermal Transient Impedance, Junction-to-Case







	DIMENSIONS IN MILLIMETE \			DIMENSIONS IN INCHES		
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
A	0.85	0. 95	1.00	0.033	0.037	0.039
	0.00		0.05	0.000		0.002
	0.30		0.50	0.012	0.016	0.020
c	0.15	0. 20	0. 25	0.006	0.008	0.010
			_		0. 205	
D1		4. 35			0.171	
		5. 55	_		0.219	
		6.05	_		0. 238	
E2		3. 625			0. 143	
e	e 1. 27 BSC		0.050 BSC			
L	0.45	0. 55	0.65	0.018	0.022	0.026
L1	0		0. 15	0		0.006
L2	0. 68 REF			0. 027 REF		
	0°		10°	0°		10°

NOTE

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm



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